

Notice of References CitedApplication/Control No.
10/004,538Applicant(s)/Patent Under Reexam
Naka et al.Examiner
Gail VerbitskyArt Unit
2859

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NON-PATENT DOCUMENTS

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
U	Thin Film Thermal Conductivity Meter, Amer et al. 1997
V	Assessment of heat Flow through Bulk geologic Material, Green et al. Joint Conferences. 1997
W	Development of NPL Guarded Hot Plate Emissometer, Stacey et al. Joint Conferences. 1997.
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¹ A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).¹ Dates in MM-YYYY format are publication dates.² Classifications may be U.S. or foreign.